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(54) Title: APPARATUS AND METHOD FOR SETTING A PRECISE VOLTAGE ON TEST CIRCUITS

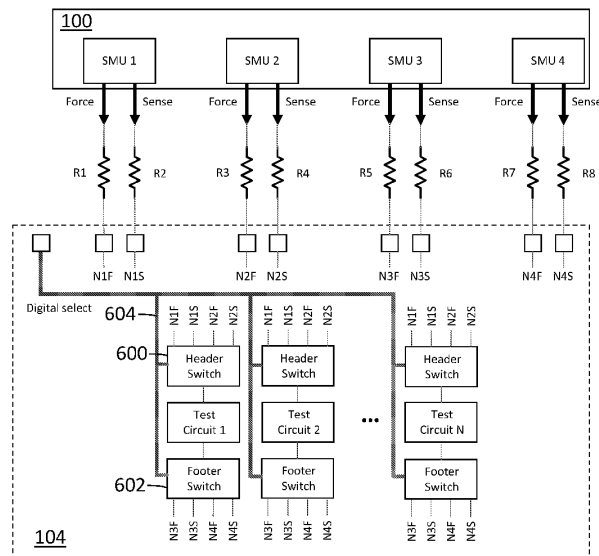


FIG. 6

(57) Abstract: An apparatus has a semiconductor wafer hosting rows and columns of chips, where the rows and columns of chips are separated by scribe lines. Selection circuitry is positioned within the scribe lines. The selection circuitry is connected to test circuits in the scribe lines. The selection circuitry operates to enable voltage control at a single test circuit while disabling all other test circuits and includes a header switch for each test circuit and a footer switch for each test circuit.

[Continued on next page]

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